

We focus on power.

2012-02-01

TAPERED AMPLIFIER

GaAs Semiconductor Laser Diode



Revision 1.00



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General Product Information

Product	Application
850 nm Tapered Amplifier	Spectroscopy
C-Mount Package	



Absolute Maximum Ratings

	Symbol	Unit	min	typ	max
Storage Temperature	T_S	°C	-40		85
Operational Temperature at Case	T_{C}	°C	0		50
Forward Current	I _F	А			3.5
Reverse Voltage	V_R	V			2
Output Power	P_{opt}	W			2.2

non condensing
non condensing
Stress in excess of one of the Absolute Maximum
Ratings can cause permanent damage to the device.

Recommended Operational Conditions

	Symbol	Unit	min	typ	max
Operational Temperature at Case	T _C	°C	5		40
Forward Current	I _F	А			3.2
Input Power	P _{input}	mW	10		50
Output Power	P _{opt}	W			2.0

Measurement Conditions / Comments
non condensing
with proper injection from a seed laser

Characteristics at T_{LD} = 25 °C at Begin Of Life

Parameter	Symbol	Unit	min	typ	max
Center Wavelength	λς	nm		852	
Gain Width (FWHM)	Δλ	nm		20	
Temperature Coefficient of Wavelength	dλ / dT	nm / K		0.25	
Amplification	P_{opt}	dB	16	22	
Operational Current @ P _{opt} = 2.0 W	I _{op Gain}	А			3.2
Output Power @ I _F = 3.2 A	P _{opt}	W	2.0		
Cavity Length	L	μm		4000	

Measurement Conditions / Comments
see graph on page 4
at 850 nm
with proper injection from a seed laser





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Characteristics at T _{am}	haracteristics at T _{amb} 25 °C at Begin Of Life cont'd					
Parameter	Symbol	Unit	min	typ	max	Measurement C
Input Aperture (at rear side)	d _{input}	μm		3		
Output Aperture (at front side)	d _{output}	μm		210		
Astigmatism	А	μm		700		depending on op
Divergence parallel (1/e²)	$\Theta_{ }$	0		15		full beam diverge
Divergence perpendicular (1/e²)	Θ_{\perp}	0		31		full beam diverg
Polarization				TE		E field parallel to

Measurement Conditions / Comments				
dependir	ng on operatin	g condition	ns	
full bean	n divergence			
full bean	n divergence			
E field pa	arallel to junct	ion plane		

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RWE/RWL		TPL

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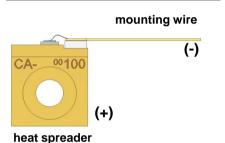
Package Dimensions

Parameter	Symbol	Unit	min	typ	max
Height of Emission Plane	h	mm	7.05	7.20	7.35
C-Mount Thickness	t	mm		4.15	

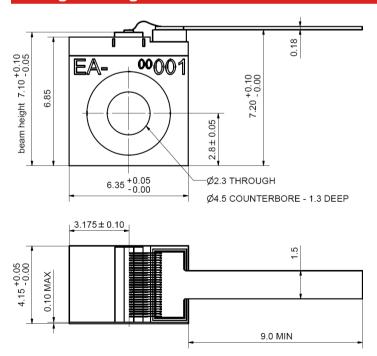
Measurement Conditions / Comments

Package Pinout

Cathode (-)	Mounting Wire
Anode (+)	Housing



Package Drawings



Z11-SPEC-CMT04-0000





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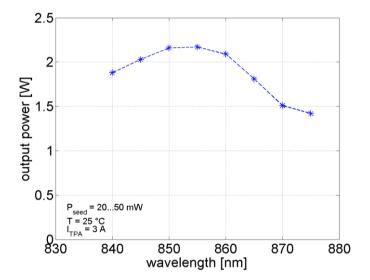
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Typical Measurement Results

Output power with seeding at different wavelengths



Performance figures, data and any illustrative material provided in this specification are typical and must be specifically confirmed in writing by eagleyard Photonics before they become applicable to any particular order or contract. In accordance with the eagleyard Photonics policy of continuous improvement specifications may change without notice.

Ordering Information:



800 Village Walk #316 Guilford, CT 06437 Ph: 203-401-8093

Email orders to: sales@xsoptix.com
Fax orders to: 800-878-7282

Unpacking, Installation and Laser Safety

Unpacking the laser diodes should only be done at electrostatic safe workstations (EPA). Though protection against electro static discharge (ESD) is implemented in the laser package, charges may occur at surfaces. Please store this product in its original package at a dry, clean place until final use. During device installation, ESD protection has to be maintained.

The TPA diode type is known to be sensitive against thermal stress. It should not be operated without appropriate injection from a seed laser. Operating at moderate temperatures on proper heat sinks willl contribute to a long lifetime of the diode. The chip should be protected against moisture. A water vapor content below 5000 ppm is recommended for applications with high reliability requirements.

The laser emission from this diode is close to the invisible infrared region of the electromagnetic spectrum. Avoid direct and/or indirect exposure to the free running beam. Collimating the free running beam with optics as common in optical instruments will increase threat to the human eye.

Each laser diode will come with an individual test protocol verifying the parameters given in this document.

